

CoolSiC™ M1

CoolSiC™ MOSFET 650 V G1

The 650 V CoolSiC™ is built over the solid silicon carbide technology developed in Infineon in more than 20 years. Leveraging the wide bandgap SiC material characteristics, the 650V CoolSiC™ MOSFET offers a unique combination of performance, reliability and ease of use. Suitable for high temperature and harsh operations, it enables the simplified and cost effective deployment of the highest system efficiency.

Features

- Optimized switching behavior at higher currents
- Commutation robust fast body diode with low Q_{fr}
- Superior gate oxide reliability
- $T_{j,max}=175^{\circ}C$ and excellent thermal behavior
- Lower $R_{DS(on)}$ and pulse current dependency on temperature
- Increased avalanche capability
- Compatible with standard drivers
- Kelvin source provides up to 4 times lower switching losses

Benefits

- Unique combination of high performance, high reliability and ease of use
- Ease of use and integration
- Suitable for topologies with continuous hard commutation
- Higher robustness and system reliability
- Efficiency improvement
- Reduced system size leading to higher power density

Potential applications

- SMPS
- UPS (uninterruptable power supplies)
- Solar PV inverters
- EV charging infrastructure
- Energy storage and battery formation
- Class D amplifiers

Product validation

Fully qualified according to JEDEC for Industrial Applications

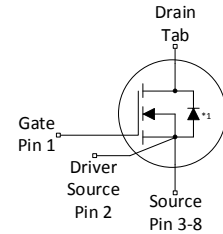
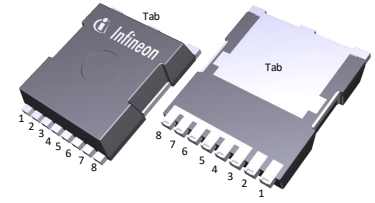
Please note: The source and sense source pins are not exchangeable. Their exchange might lead to malfunction.

Table 1 Key Performance Parameters

| Parameter | Value | Unit |
|------------------------------|-------|------|
| $V_{DS} @ T_J = 25^{\circ}C$ | 650 | V |
| $R_{DS(on),typ}$ | 163 | mΩ |
| $R_{DS(on),max}$ | 217 | mΩ |
| $Q_{G,typ}$ | 10 | nC |
| $I_{DM,max}$ | 31 | A |
| $Q_{oss} @ 400 V$ | 27 | nC |
| $E_{oss} @ 400 V$ | 4.1 | μJ |

| Type/Ordering Code | Package | Marking | Related Links |
|--------------------|-----------|----------|----------------|
| IMT65R163M1H | PG-HSOF-8 | 65R163M1 | see Appendix A |

TOLL



*1: Internal body diode

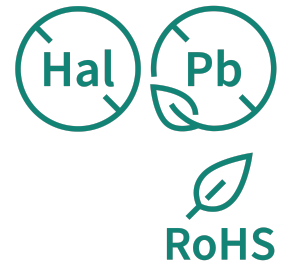


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1 Maximum ratings

at $T_j = 25\text{ °C}$, unless otherwise specified.

Note: for optimum lifetime and reliability, Infineon recommends operating conditions that do not exceed 80% of the maximum ratings stated in this datasheet.

Table 2 Maximum ratings

| Parameter | Symbol | Values | | | Unit | Note/ Test Condition |
|--|-----------|--------|------|----------|------|---|
| | | Min. | Typ. | Max. | | |
| Continuous DC drain current ¹⁾ | I_{DDC} | - | - | 19 13 | A | $T_c = 25\text{ °C}$ $T_c = 100\text{ °C}$ |
| Peak drain current ²⁾ | I_{DM} | - | - | 31 | A | $T_c = 25\text{ °C}$, $V_{GS} = 18\text{ V}$ |
| Avalanche energy, single pulse | E_{AS} | - | - | 49 | mJ | $I_D = 1.8\text{ A}$, $V_{DD} = 50\text{ V}$; see table 11 |
| Avalanche energy, repetitive | E_{AR} | - | - | 0.24 | mJ | $I_D = 1.8\text{ A}$, $V_{DD} = 50\text{ V}$; see table 11 |
| Avalanche current, single pulse | I_{AS} | - | - | 1.8 | A | - |
| MOSFET dv/dt ruggedness | dv/dt | - | - | 200 | V/ns | $V_{DS} = 0 \dots 400\text{ V}$ |
| Gate source voltage (static) ³⁾ | V_{GS} | -5 | - | 23 | V | - |
| Gate source voltage (transient) | V_{GS} | -7 | - | 25 | V | $t_{pulse} \leq 1\%$ duty cycle/ f_{sw} |
| Power dissipation | P_{tot} | - | - | 106 | W | $T_c = 25\text{ °C}$ |
| Storage temperature | T_{stg} | -55 | - | 150 | °C | - |
| Operating junction temperature | T_j | -55 | - | 175 | °C | - |
| Mounting torque | - | - | - | n.a. | Ncm | - |
| Continuous reverse drain current ¹⁾ | I_{SDC} | - | - | 19 12 | A | $V_{GS} = 18\text{ V}$, $T_c = 25\text{ °C}$ $V_{GS} = 0\text{ V}$, $T_c = 25\text{ °C}$ |
| Peak reverse drain current ²⁾ | I_{SM} | - | - | 31 | A | $T_c = 25\text{ °C}$, $t_p \leq 250\text{ ns}$ |
| Insulation withstand voltage | V_{ISO} | - | - | n.a. | V | V_{rms} , $T_c = 25\text{ °C}$, $t = 1\text{ min}$ |

¹⁾ Limited by $T_{j,max}$.

²⁾ Pulse width t_{pulse} limited by $T_{j,max}$.

³⁾ The maximum gate-source voltage in the application design should be in accordance to IPC-9592B.

2 Thermal characteristics

Table 3 Thermal characteristics

| Parameter | Symbol | Values | | | Unit | Note/ Test Condition |
|---|---------------|--------|------|------|------|---|
| | | Min. | Typ. | Max. | | |
| Thermal resistance, junction - case | $R_{th(j-c)}$ | - | - | 1.41 | °C/W | - |
| Thermal resistance, junction - ambient | $R_{th(j-a)}$ | - | - | 62 | °C/W | device on PCB, minimal footprint |
| Thermal resistance, junction - ambient, SMD version | $R_{th(j-a)}$ | - | 35 | 45 | °C/W | Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm ² (one layer, 70µm thickness) copper area for drain connection and cooling. PCB is vertical without air stream cooling. |
| Soldering temperature, wave- & reflow soldering allowed | T_{sold} | - | - | 260 | °C | reflow MSL2 |

3 Operating range

Table 4 Operating range

| Parameter | Symbol | Values | | | Unit | Note/ Test Condition |
|---|---------------|--------|------|------|------|----------------------|
| | | Min. | Typ. | Max. | | |
| Gate-source voltage operating range including undershoots ⁴⁾ | V_{GS} | -2 | - | 20 | V | - |
| Recommended turn-on voltage | $V_{GS(on)}$ | - | 18 | - | V | - |
| Recommended turn-off voltage | $V_{GS(off)}$ | - | 0 | - | V | - |

4)

Important notice: If the gate source voltage of the device in application exceeds the operating range (Table 4), the device $R_{DS(on)}$ and $V_{GS(th)}$ might exceed the maximum value stated in the datasheet at the end of the lifetime of the device. In order to ensure sound operation of the device over the planned lifetime, the maximum ratings (Table 2) and the CoolSiC™ MOSFET 650V M1 trench power device application note AN_1907_PL52_1911_144109 must be considered.

4 Electrical characteristics

at $T_j = 25\text{ °C}$, unless otherwise specified

Table 5 Static characteristics

| Parameter | Symbol | Values | | | Unit | Note/ Test Condition |
|--------------------------------------|--------------|--------|------------|----------|------------------|---|
| | | Min. | Typ. | Max. | | |
| Drain-source voltage | V_{DSS} | 650 | - | - | V | $V_{GS} = 0\text{ V}$, $I_D = 0.17\text{ mA}$ |
| Gate threshold voltage ⁵⁾ | $V_{GS(th)}$ | 3.5 | 4.5 | 5.7 | V | $V_{DS} = V_{GS}$, $I_D = 1.7\text{ mA}$ |
| Zero gate voltage drain current | I_{DSS} | - | 1 3 | 100 - | μA | $V_{DS} = 650\text{ V}$, $V_{GS} = 0\text{ V}$, $T_j = 25\text{ °C}$ $V_{DS} = 650\text{ V}$, $V_{GS} = 0\text{ V}$, $T_j = 175\text{ °C}$ |
| Gate-source leakage current | I_{GSS} | - | - | 100 | nA | $V_{GS} = 20\text{ V}$, $V_{DS} = 0\text{ V}$ |
| Drain-source on-state resistance | $R_{DS(on)}$ | - | 163 228 | 217 - | $\text{m}\Omega$ | $V_{GS} = 18\text{ V}$, $I_D = 5.7\text{ A}$, $T_j = 25\text{ °C}$ $V_{GS} = 18\text{ V}$, $I_D = 5.7\text{ A}$, $T_j = 175\text{ °C}$ |
| Internal gate resistance | $R_{G,int}$ | - | 16.0 | - | Ω | $f = 1\text{ MHz}$ |

⁵⁾ Tested after 1 ms pulse at $V_{GS} = +20\text{ V}$.

Table 6 Dynamic characteristics

| Parameter | Symbol | Values | | | Unit | Note/ Test Condition |
|--|--------------|--------|------|------|------|--|
| | | Min. | Typ. | Max. | | |
| Input capacitance | C_{iss} | - | 320 | - | pF | $V_{GS} = 0\text{ V}$, $V_{DS} = 400\text{ V}$, $f = 250\text{ kHz}$ |
| Reverse transfer capacitance | C_{rss} | - | 4.8 | - | pF | $V_{GS} = 0\text{ V}$, $V_{DS} = 400\text{ V}$, $f = 250\text{ kHz}$ |
| Output capacitance ⁶⁾ | C_{oss} | - | 45 | 58 | pF | $V_{GS} = 0\text{ V}$, $V_{DS} = 400\text{ V}$, $f = 250\text{ kHz}$ |
| Output charge ⁶⁾ | Q_{oss} | - | 27 | 35 | nC | calculation based on C_{oss} |
| Effective output capacitance, energy related ⁷⁾ | $C_{o(er)}$ | - | 52 | - | pF | $V_{GS} = 0\text{ V}$, $V_{DS} = 0\text{...}400\text{ V}$ |
| Effective output capacitance, time related ⁸⁾ | $C_{o(tr)}$ | - | 68 | - | pF | $I_D = \text{constant}$, $V_{GS} = 0\text{ V}$, $V_{DS} = 0\text{...}400\text{ V}$ |
| Turn-on delay time | $t_{d(on)}$ | - | 5.5 | - | ns | $V_{DD} = 400\text{ V}$, $V_{GS} = 0/18\text{ V}$, $I_D = 5.7\text{ A}$, $R_{G,ext} = 1.8\text{ }\Omega$; see table 10 |
| Rise time | t_r | - | 5.9 | - | ns | $V_{DD} = 400\text{ V}$, $V_{GS} = 0/18\text{ V}$, $I_D = 5.7\text{ A}$, $R_{G,ext} = 1.8\text{ }\Omega$; see table 10 |
| Turn-off delay time | $t_{d(off)}$ | - | 8.6 | - | ns | $V_{DD} = 400\text{ V}$, $V_{GS} = 0/18\text{ V}$, $I_D = 5.7\text{ A}$, $R_{G,ext} = 1.8\text{ }\Omega$; see table 10 |
| Fall time | t_f | - | 10.0 | - | ns | $V_{DD} = 400\text{ V}$, $V_{GS} = 0/18\text{ V}$, $I_D = 5.7\text{ A}$, $R_{G,ext} = 1.8\text{ }\Omega$; see table 10 |

- 6) Maximum specification is defined by calculated six sigma upper confidence bound.
 7) $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 400 V.
 8) $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 400 V.

Table 7 Gate charge characteristics

| Parameter | Symbol | Values | | | Unit | Note/ Test Condition |
|-------------------------------|--------------|--------|------|------|------|--|
| | | Min. | Typ. | Max. | | |
| Plateau gate to source charge | $Q_{GS(pl)}$ | - | 2 | - | nC | $V_{DD} = 400\text{ V}$, $I_D = 5.7\text{ A}$, $V_{GS} = 0\text{ to }18\text{ V}$ |
| Gate to drain charge | Q_{GD} | - | 2 | - | nC | $V_{DD} = 400\text{ V}$, $I_D = 5.7\text{ A}$, $V_{GS} = 0\text{ to }18\text{ V}$ |
| Total gate charge | Q_G | - | 10 | - | nC | $V_{DD} = 400\text{ V}$, $I_D = 5.7\text{ A}$, $V_{GS} = 0\text{ to }18\text{ V}$ |

Table 8 Reverse diode characteristics

| Parameter | Symbol | Values | | | Unit | Note/ Test Condition |
|--|-----------|--------|------|------|------|---|
| | | Min. | Typ. | Max. | | |
| Drain-source reverse voltage | V_{SD} | - | 4.0 | - | V | $V_{GS} = 0\text{ V}$, $I_S = 5.7\text{ A}$, $T_j = 25\text{ °C}$ |
| MOSFET forward recovery time | t_{fr} | - | 17.0 | - | ns | $V_{DD} = 400\text{ V}$, $I_S = 5.7\text{ A}$, $di_S/dt = 1000\text{ A}/\mu\text{s}$; see table 9 |
| MOSFET forward recovery charge ⁹⁾ | Q_{fr} | - | 39 | - | nC | $V_{DD} = 400\text{ V}$, $I_S = 5.7\text{ A}$, $di_S/dt = 1000\text{ A}/\mu\text{s}$; see table 9 |
| MOSFET peak forward recovery current | I_{frm} | - | 4.6 | - | A | $V_{DD} = 400\text{ V}$, $I_S = 5.7\text{ A}$, $di_S/dt = 1000\text{ A}/\mu\text{s}$; see table 9 |

⁹⁾ Q_{fr} includes Q_{oss} .

5 Electrical characteristics diagrams

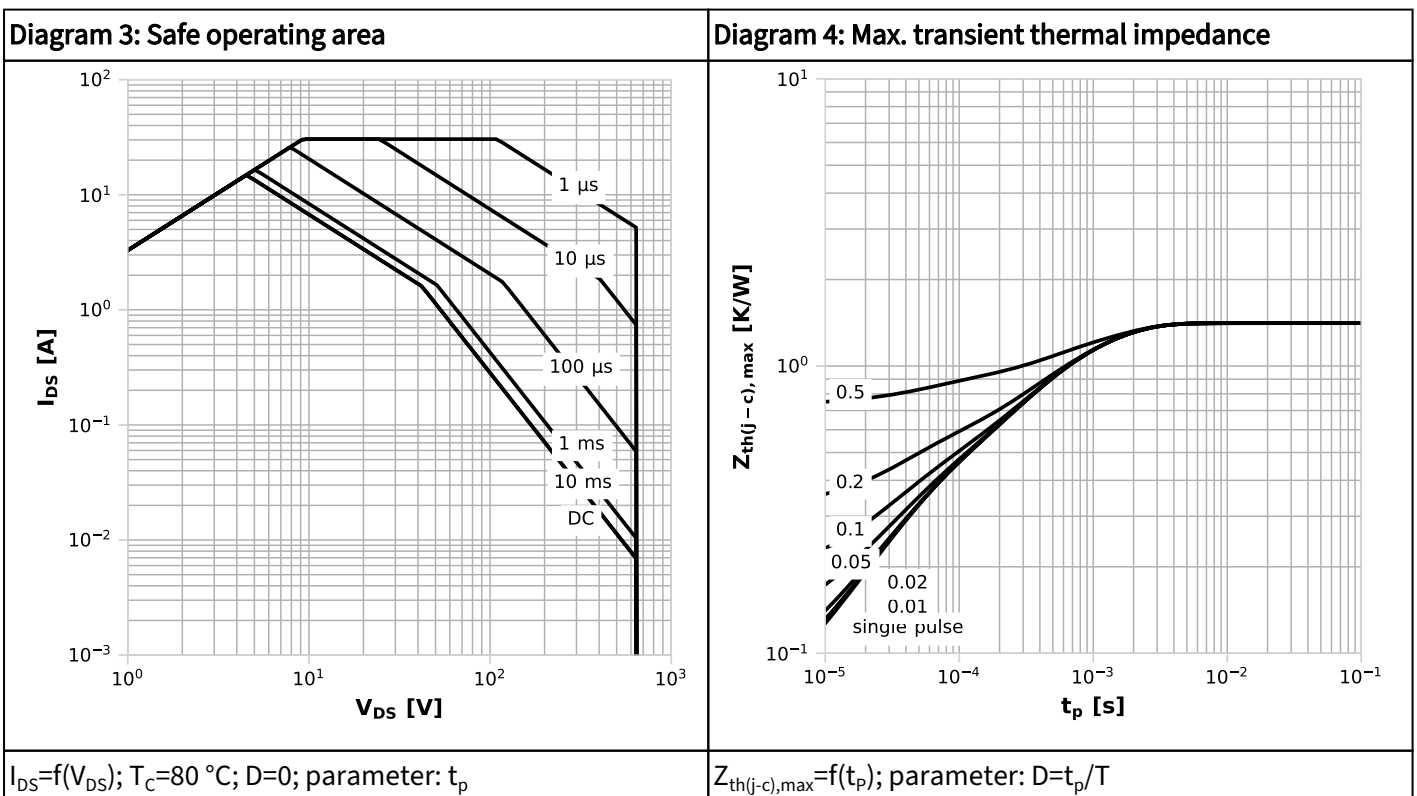
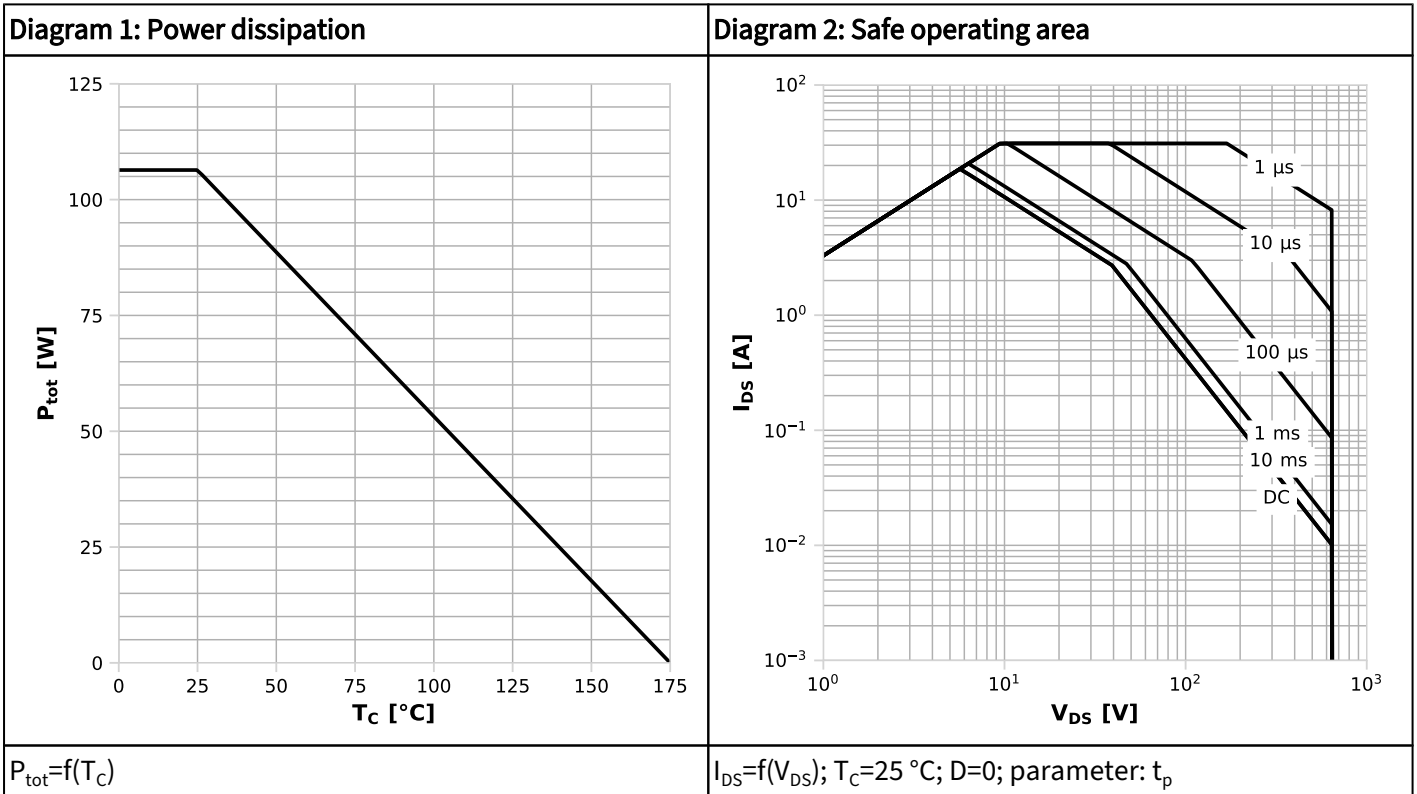
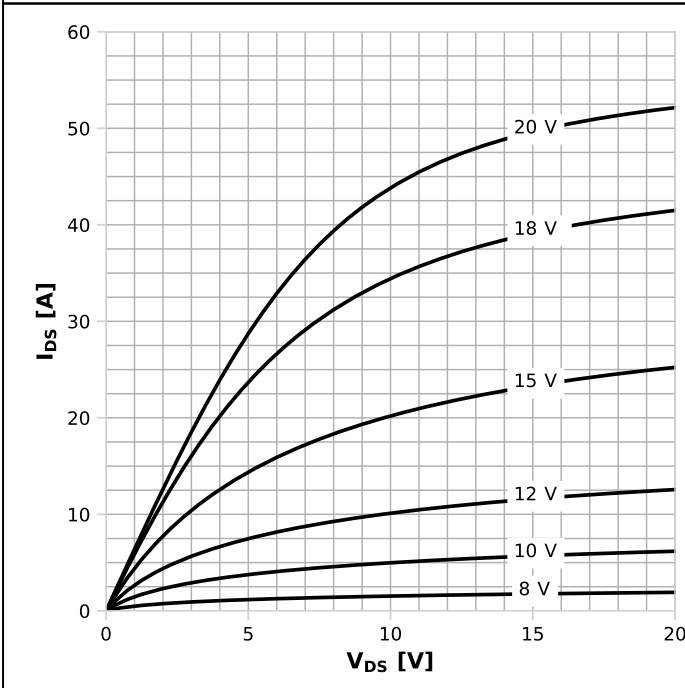
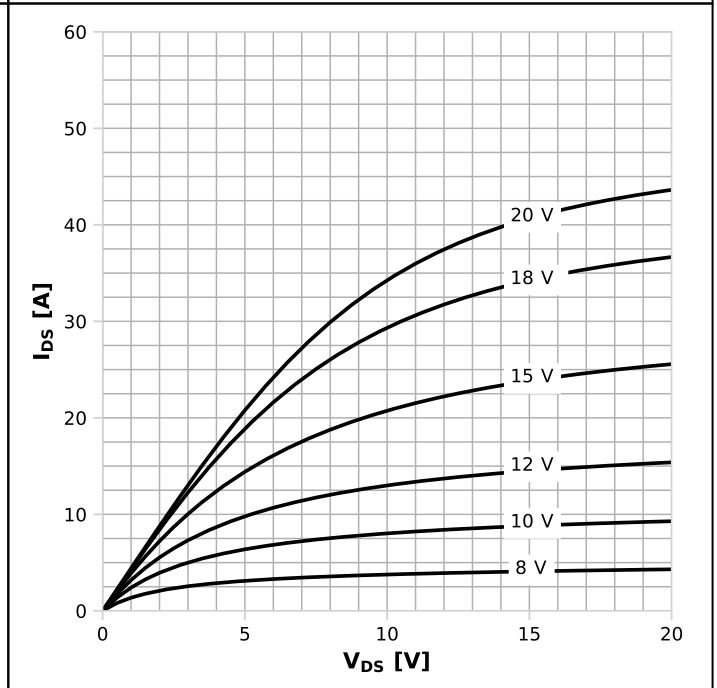


Diagram 5: Typ. output characteristics



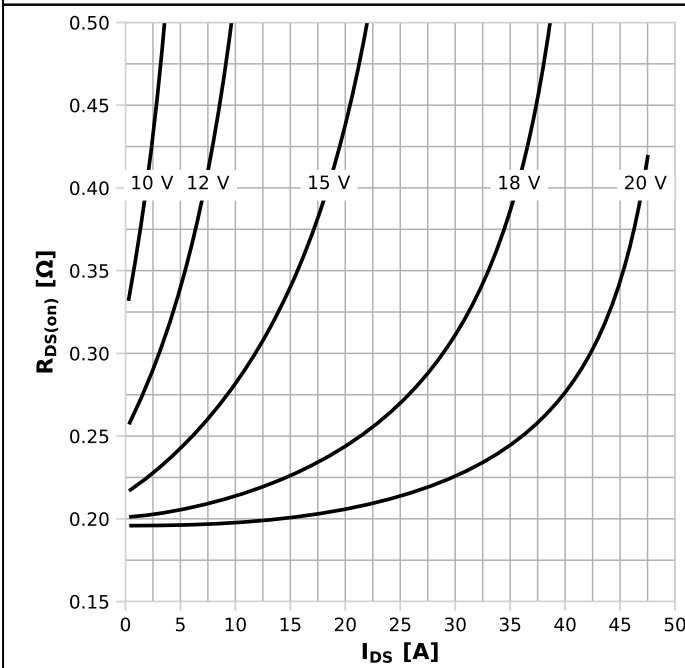
$I_{DS}=f(V_{DS}); T_j=25\text{ °C}; \text{parameter: } V_{GS}$

Diagram 6: Typ. output characteristics



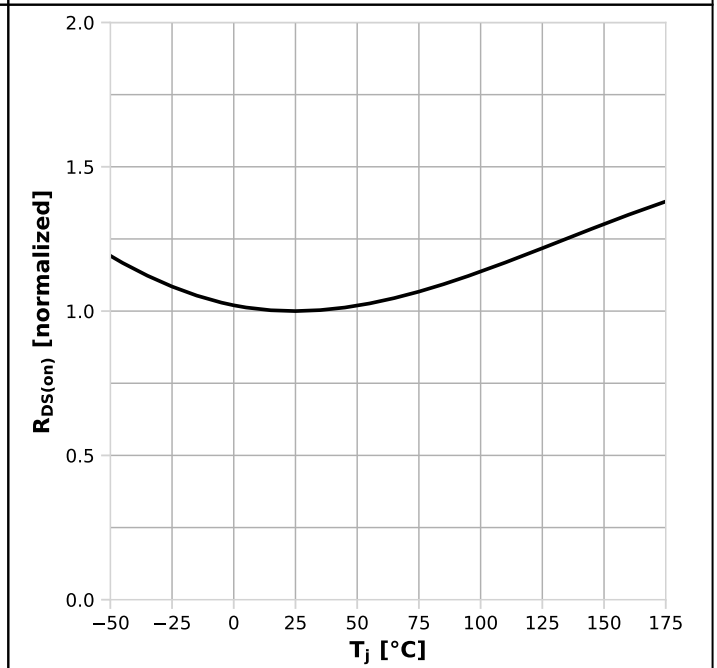
$I_{DS}=f(V_{DS}); T_j=175\text{ °C}; \text{parameter: } V_{GS}$

Diagram 7: Typ. drain-source on-state resistance



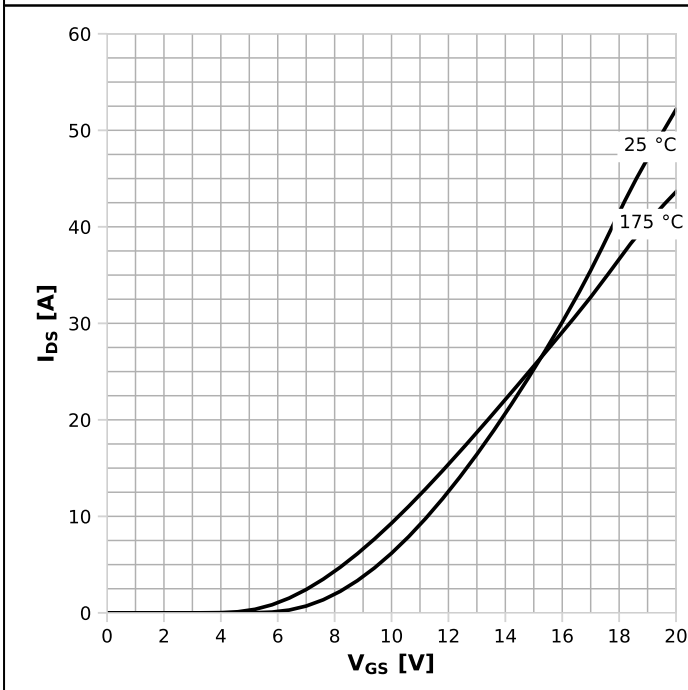
$R_{DS(on)}=f(I_{DS}); T_j=125\text{ °C}; \text{parameter: } V_{GS}$

Diagram 8: Drain-source on-state resistance



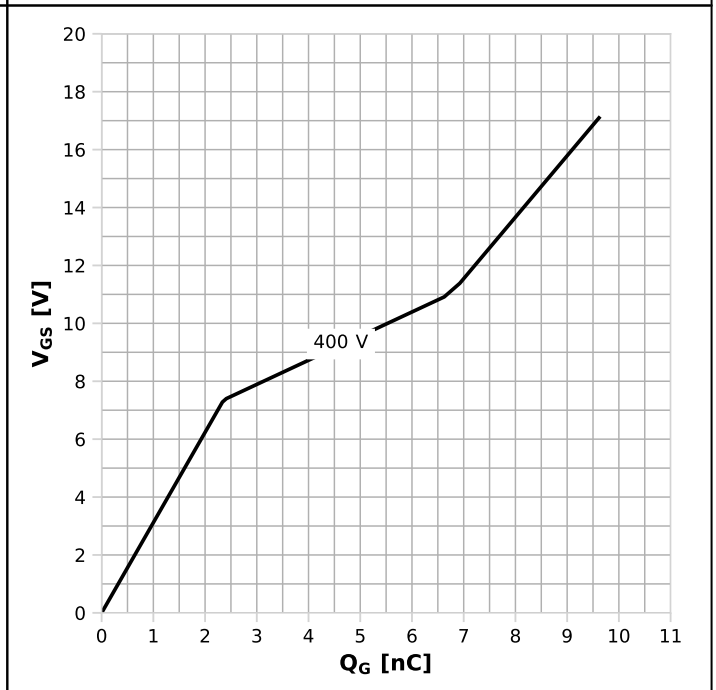
$R_{DS(on)}=f(T_j); I_D=5.7\text{ A}; V_{GS}=18\text{ V}$

Diagram 9: Typ. transfer characteristics



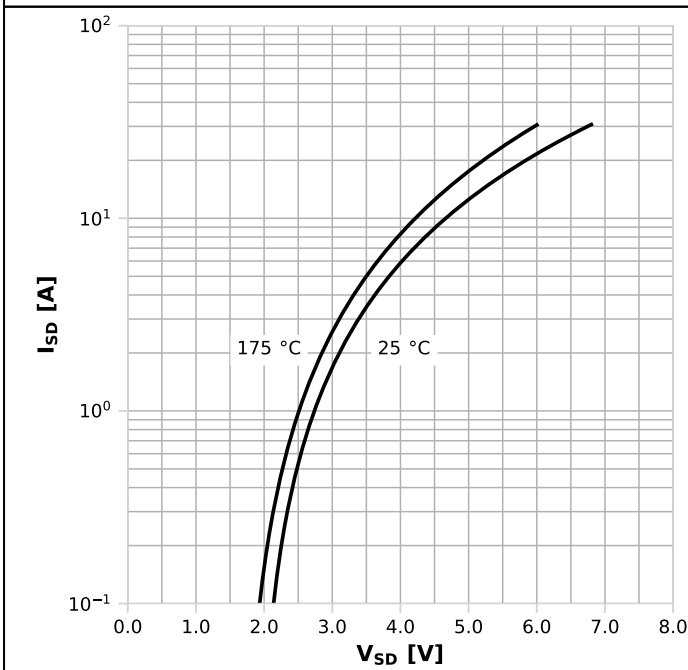
$I_{DS}=f(V_{GS}); V_{DS}=20V; \text{parameter: } T_j$

Diagram 10: Typ. gate charge



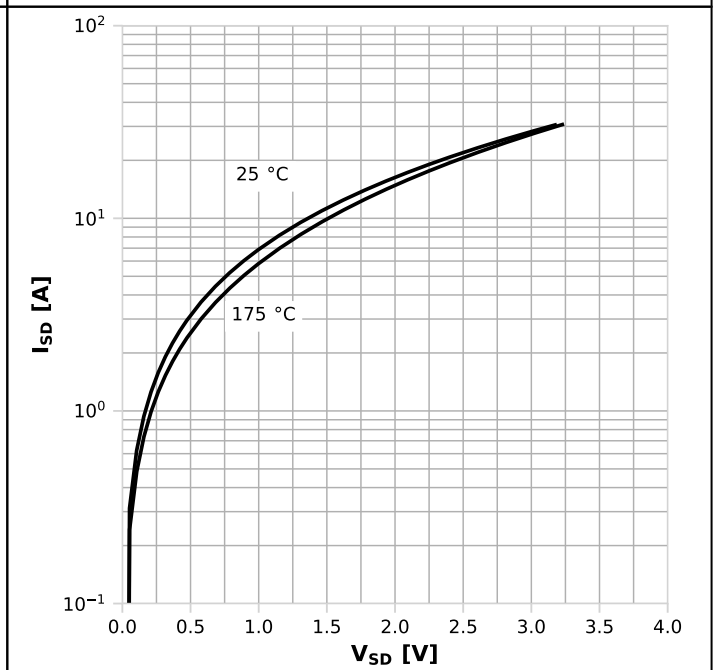
$V_{GS}=f(Q_G); I_D=5.7 \text{ A pulsed}; \text{parameter: } V_{DD}$

Diagram 11: Typ. reverse drain current characteristics



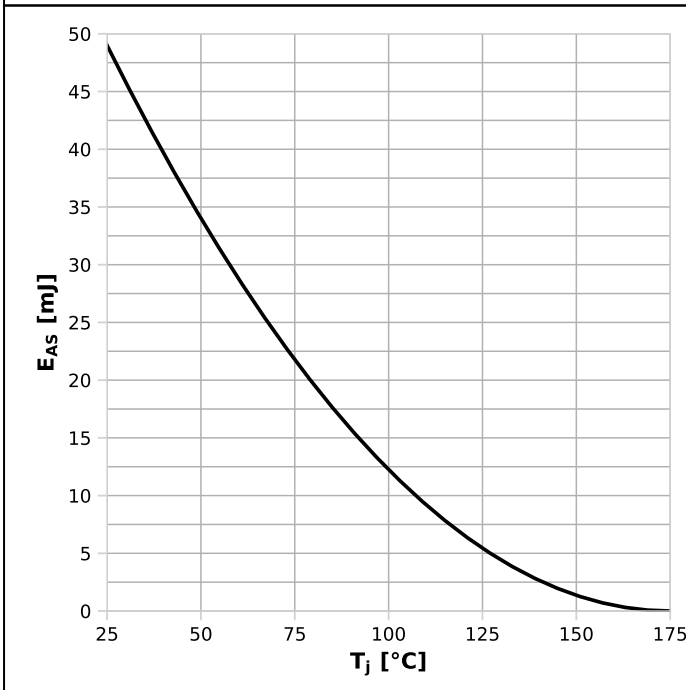
$I_{SD}=f(V_{SD}); V_{GS}=0 \text{ V}; \text{parameter: } T_j$

Diagram 12: Typ. reverse drain current characteristics



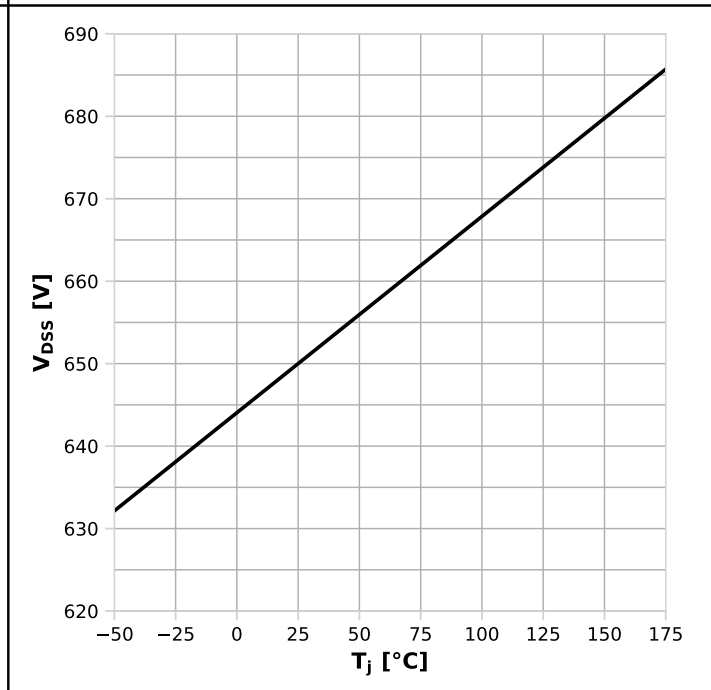
$I_{SD}=f(V_{SD}); V_{GS}=18 \text{ V}; \text{parameter: } T_j$

Diagram 13: Avalanche energy



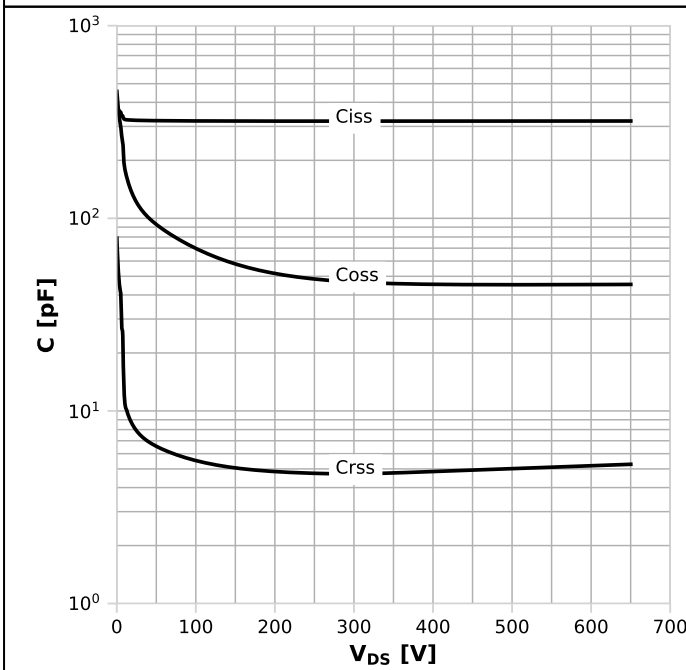
$E_{AS}=f(T_j); I_D=1.8\text{ A}; V_{DD}=50\text{ V}$

Diagram 14: Drain-source breakdown voltage



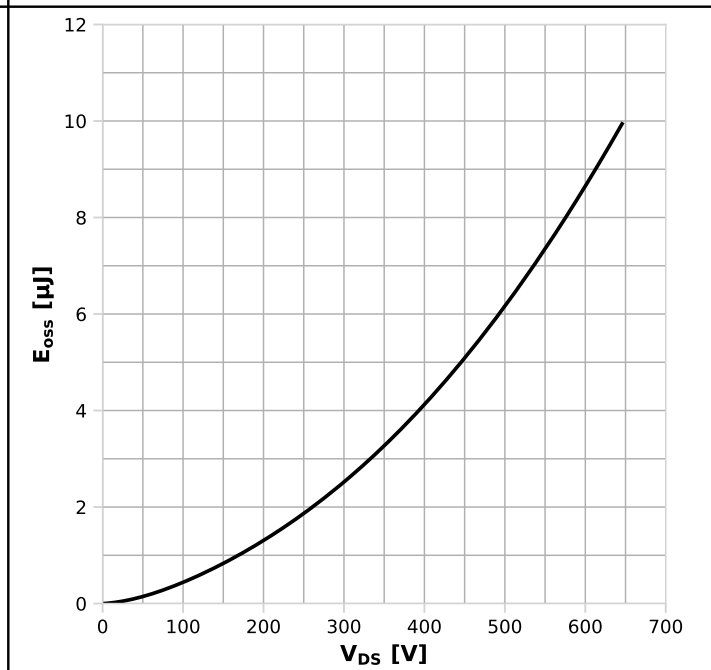
$V_{DSS}=f(T_j); I_D=0.17\text{ mA}$

Diagram 15: Typ. capacitances



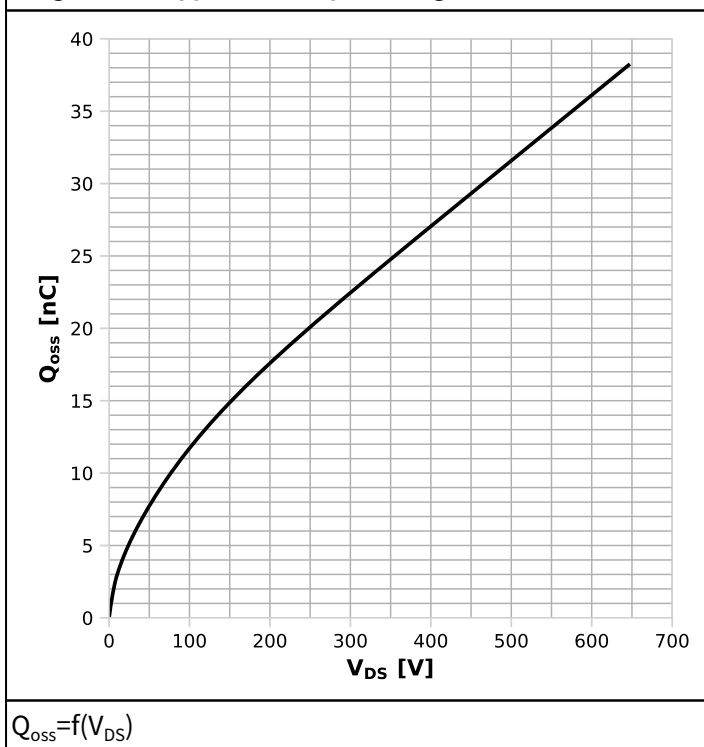
$C=f(V_{DS}); V_{GS}=0\text{ V}; f=250\text{ kHz}$

Diagram 16: Typ. Coss stored energy



$E_{oss}=f(V_{DS})$

Diagram 17: Typ. Qoss output charge



6 Test Circuits

Table 9 Body diode characteristics (CoolSiC)

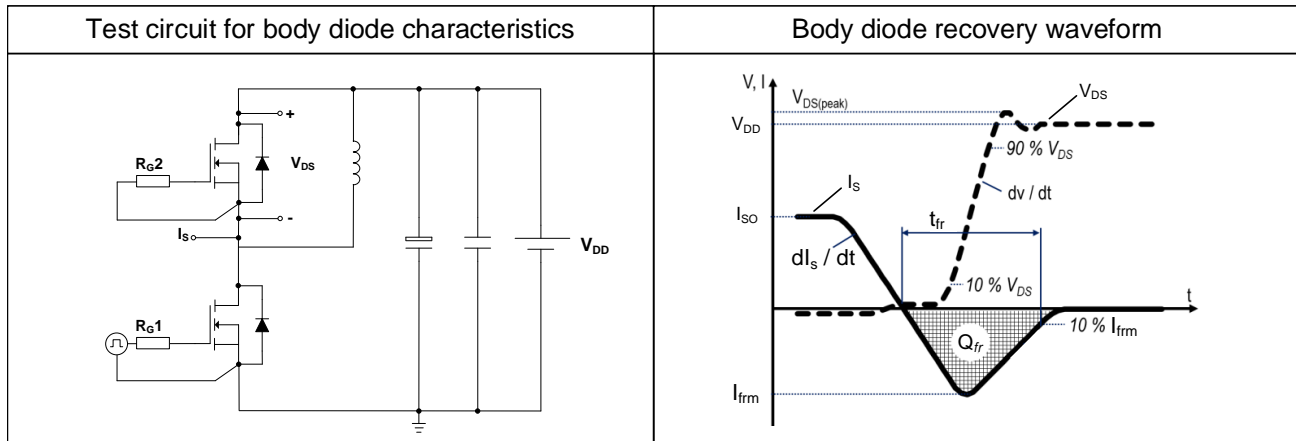


Table 10 Switching times (CoolSiC)

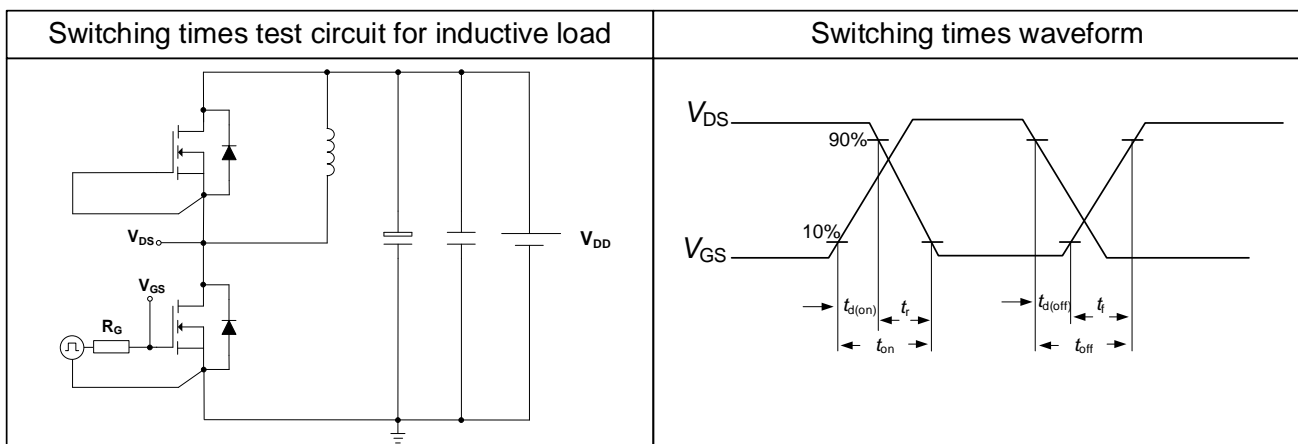
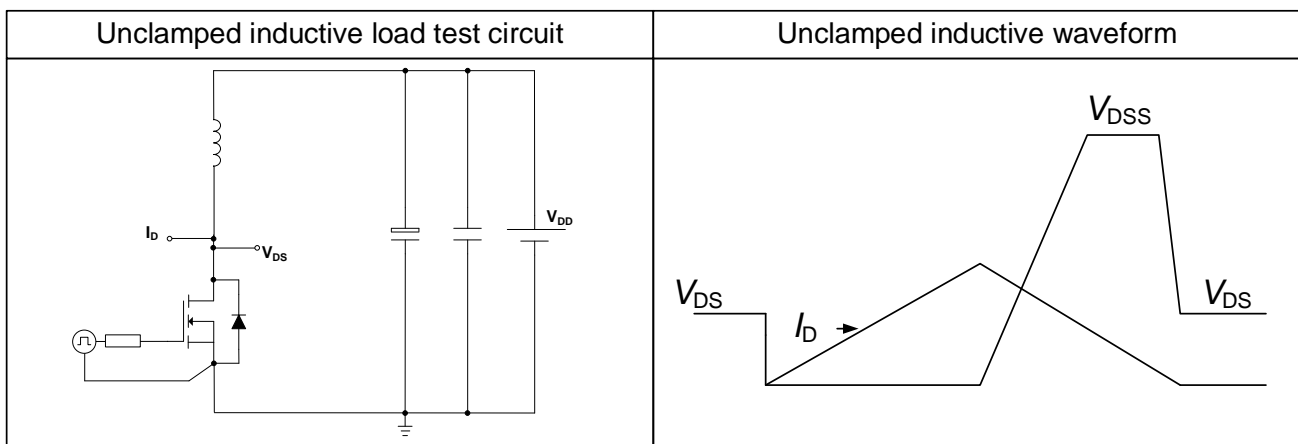
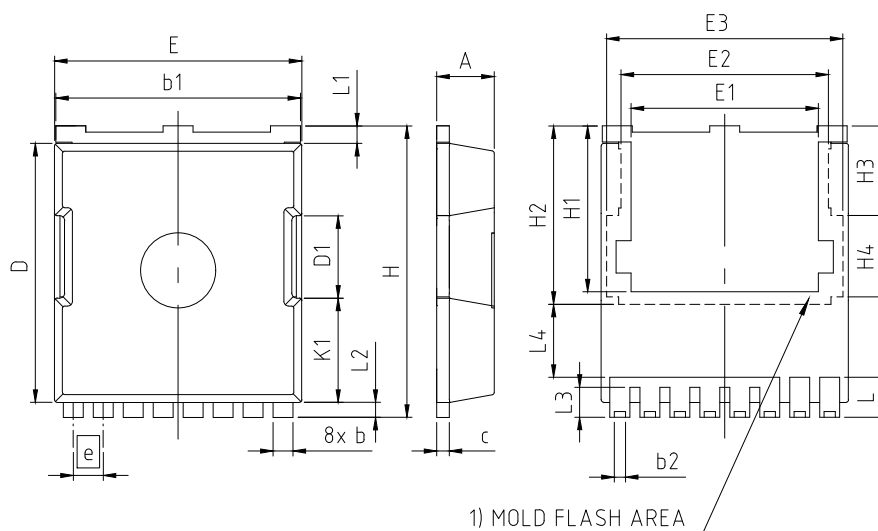


Table 11 Unclamped inductive load



7 Package Outlines



1) MOLD FLASH AREA

| PACKAGE - GROUP NUMBER: PG-HSOF-8-U02 | | |
|---------------------------------------|-------------|-------|
| DIMENSIONS | MILLIMETERS | |
| | MIN. | MAX. |
| A | 2.20 | 2.40 |
| b | 0.70 | 0.90 |
| b1 | 9.70 | 9.90 |
| b2 | 0.42 | 0.50 |
| c | 0.40 | 0.60 |
| D | 10.28 | 10.58 |
| D1 | 3.30 | |
| E | 9.70 | 10.10 |
| E1 | 7.50 | |
| E2 | 8.50 | |
| E3 | 9.46 | |
| e | 1.20 (BSC) | |
| H | 11.48 | 11.88 |
| H1 | 6.55 | 6.95 |
| H2 | 7.15 | |
| H3 | 3.59 | |
| H4 | 3.26 | |
| N | 8 | |
| K1 | 4.18 | |
| L | 1.40 | 1.80 |
| L1 | 0.50 | 0.90 |
| L2 | 0.50 | 0.70 |
| L3 | 1.00 | 1.30 |
| L4 | 2.62 | 2.81 |

1) PARTIALLY COVERED WITH MOLD FLASH

Figure 1 Outline PG-HSOF-8, dimensions in mm

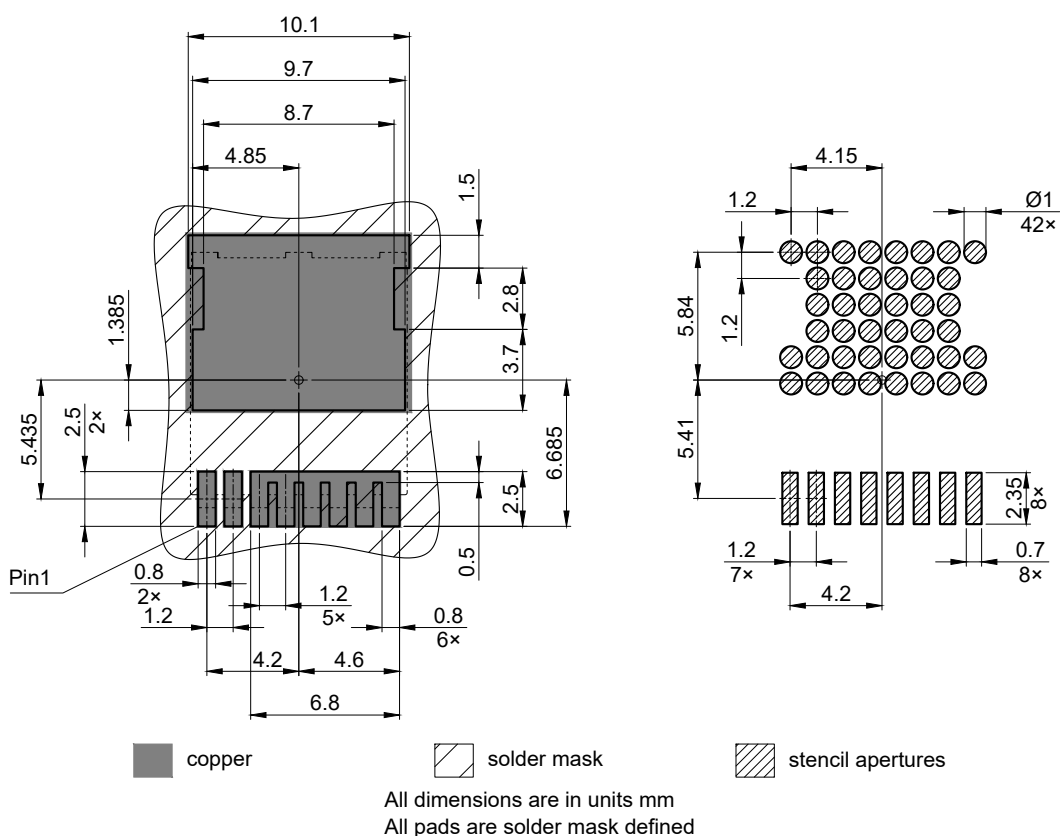
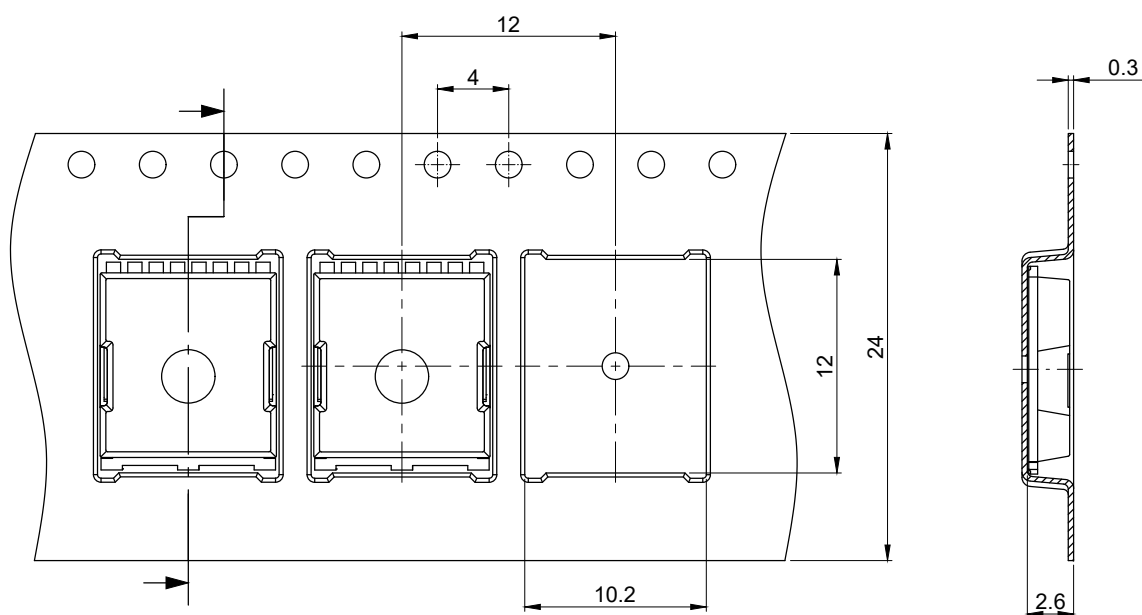


Figure 2 Footprint Drawing PG-HSOF-8, dimensions in mm



All dimensions are in units mm


The drawing is in compliance with ISO 128-30, Projection Method 1 []

Figure 3 Packaging Variant PG-HSOF-8, dimensions in mm

8 Appendix A

Table 12 Related Links

- [IFX CoolSiC CoolSiC™ MOSFET 650 V G1 Webpage](#)
- [IFX CoolSiC CoolSiC™ MOSFET 650 V G1 Application Note](#)
- [IFX CoolSiC CoolSiC™ MOSFET 650 V G1 Simulation Model](#)
- [IFX Design tools](#)

Revision History

IMT65R163M1H

Revision 2024-10-07, Rev. 2.2

Previous Revision

| Revision | Date | Subjects (major changes since last revision) |
|----------|------------|---|
| 2.0 | 2023-03-08 | Release of final version |
| 2.1 | 2024-08-26 | IDSS update, nomenclature update, datasheet layout and POD update |
| 2.2 | 2024-10-07 | Update with package footprint and outline drawing correction |

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